

Notice of References Cited	Application/Control No. 10/605,058	Applicant(s)/Patent Under Reexamination DELINE, JONATHAN	
	Examiner Khai M. Nguyen	Art Unit 2687	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2002/0068610 A1	06-2002	Anvekar et al.	455/560
	B	US-6,748,278 B1	06-2004	Maymudes, David M.	700/17
	C	US-6,295,448 B1	09-2001	Hayes et al.	455/420
	D	US-6,622,018 B1	09-2003	Erekson, Rich	455/420
	E	US-2003/0003907 A1	01-2003	Lai et al.	455/425
	F	US-2003/0041332 A1	02-2003	Allen et al.	725/106
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
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	X	

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